

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
MI22-1363SERIAL NO. 09/512968  
Filed HerewithLIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)APPLICANT  
Micron Technology, Inc.FILING DATE  
Filed HerewithGROUP 2858  
Unknown

## U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	<del>AA 00/032,184</del>		<del>Akram et al.</del>			<del>2/22/02</del>
VN	AB 5,495,667	3/5/96	Farnworth et al.	29	843	
	AC					
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## FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
	AM						
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## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AK	Advertisement for Probe Technology from the Web Page of Interconnect Devices, Inc., 1 page
AS	Good Things Come In Small BGA/CSP Packages from the Web Page of Johnstech International, Corporation, 1 page
AT	Product Description for Test Socket Contacts from the Web Page of Johnstech International, Corporation, 1 page

EXAMINER

*and Nguyen*

DATE CONSIDERED

01/26/2001

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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	AN							
	AO							
	AP							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AR	<del>Product Description for Double Ended Probes, B105Z Series, from the Web Page of Rika Denzhi America, Inc., 1 page</del>
	AS	<del>Product Description for Test Centers, RM 500 Series Probes, from the Web Page of Rika Denzhi America, Inc., 1 page</del>
	AT	<del>Product Description for Cost Effective Interconnections for High I/O Products from the Web Page of Rika Denzhi America, Inc., 1 page</del>

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## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AR		Product Description for Ball Grid Probe B1303-C3 from the Web Page of Rika Denshi America, Inc., 1 page
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*ronh Nguyen*

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M122-1363SERIAL NO.  
09/512,968LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)APPLICANT  
Micron Technology, Inc.FILING DATE  
Filed HerewithGROUP 2558  
2832

## U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA 4,560,216	12/24/85	Egawa			
VN	AB 4,754,555	7/5/88	Stillman			
VN	AC 5,475,317	12/12/95	Smith			
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AT	Product Description for Test Socket Contacts from the Web Page of Johnstech International, Corporation, 1 page

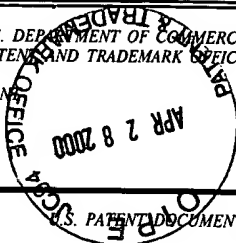
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MI22-1363SERIAL NO.  
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Micron Technology, Inc.FILING DATE  
February 24, 2000GROUP  
~~Unknown~~ 2858

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA	5,325,052	6/28/94	Yamashita			
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